JEDOS - JTAG Embedded Diagnostics Operating System

Embedded Functional Test, Diagnostics, Calibration and Programming

JEDOS™ is an embedded test & diagnostics operating system of the next generation. It is able to perform functional tests in real time using the native processor. The use of special test software or Flash resident firmware thus is completely unnecessary.

JEDOS™ provides maximum fault coverage and comprehensive diagnoses for digital, analog and mixed-signal components. The list of supported processors is constantly growing through continuous development of new JEDOS-IP. It is usable both in lab for design validation of prototypes as well as for production process and repair. The JEDOS technology is fully integrated into the software platform SYSTEM CASCON™. This enables the easy combination with Boundary Scan, Embedded Instruments and other non-invasive technologies on a single platform.

Functions	Specification
JEDOS Application Manager	Core module of JEDOS, enables handling of functional IP's, report generation and JTAG control
DDR Test	Functional at-speed / real time test of DDR devices with selectable algorithms (address test, burst test, noise test, stress test, cell test)
DDR Calibration	Functional Margin Test of DDR I/F with pre-defined parameters for the DDR RAM Controller, or automated search of case optimized parameters
Peripheral I/O Test	Functional at-speed / real time test of GPIO, UART, PCI, PCIe, Ethernet LAN, USB2.0, USB3.0
Universal Function Test	Load, execution and dynamic control of pre-compiled, JEDOS compliant IP generated by the user or from 3rd party for any kind of functional Test
In-System Device Programming	High speed programming of non-volatile devices like NAND, NOR, SPI, I2C, eMMC, MCU via streaming through communication I/F (USB2.0, USB3.0, LAN) or download from external connected USB Flash memory